

PCZ120N40M1

N-Channel eSiC Silicon Carbide Power MOSFET

1200 V, 60 A, 40 mΩ



Masters of Power Solution

Features

- High switching speed with a low gate charge
- Fast intrinsic diode with low reverse recovery
- Robust Avalanche Capability
- 100% Avalanche Tested
- Pb-free, Halogen Free, and RoHS Compliant

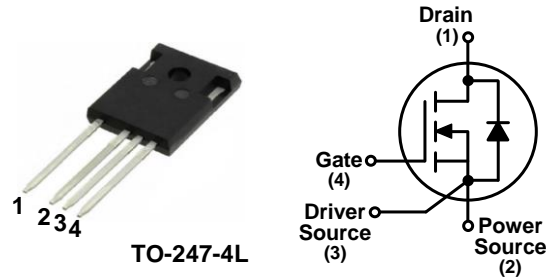
$BV_{DSS, T_C=25^\circ C}$	$I_D, T_C=25^\circ C$	$R_{DS(on), typ}$	$Q_{g, typ}$
1200 V	60 A	40 mΩ	104 nC

Benefits

- System efficiency improvement
- Higher frequency applicability
- Increased power density
- Reduced cooling effort

Applications

- Solar inverter
- EV charging station
- UPS
- Industrial power supply



Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain to Source Voltage	1200	V
V_{GS}	Gate to Source Voltage (DC)	-10 / +22	V
V_{GSop}	Recommended Operation Value	-5 / +18	V
I_D	Drain Current	Continuous ($T_C = 25^\circ C$)	60
		Continuous ($T_C = 100^\circ C$)	43
I_{DM}	Drain Current	Pulsed (Note1)	160
P_D	Power Dissipation	($T_C = 25^\circ C$)	319
		Derate Above $25^\circ C$	2.1
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 175	$^\circ C$
T_L	Maximum Lead Temperature for Soldering, 1/8" from Case for 10 Seconds	260	$^\circ C$

※Note 1 : Limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.47	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

Package Marking and Ordering Information

Part Number	Top Marking	Package	Packing Method	Quantity
PCZ120N40M1	PCZ120N40M1	TO-247-4L	Tube	30 units

Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
--------	-----------	-----------------	-----	-----	-----	------

Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 1\text{ mA}$	1200			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}$		1	100	μA
		$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}, T_J = 175^\circ\text{C}$		10		
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = +22\text{ V}, V_{DS} = 0\text{ V}$			+100	nA
		$V_{GS} = -10\text{ V}, V_{DS} = 0\text{ V}$			-100	

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 10\text{ mA}$ (tested after $V_{GS} = 22\text{ V}, 1\text{ ms pulse}$)	2.0	3.0	4.5	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 18\text{ V}, I_D = 30\text{ A}$		40	56	$\text{m}\Omega$
		$V_{GS} = 18\text{ V}, I_D = 30\text{ A}, T_J = 175^\circ\text{C}$		64		
g_{fs}	Transconductance	$V_{DS} = 20\text{ V}, I_D = 30\text{ A}$		16.1		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 800\text{ V}, V_{GS} = 0\text{ V}, f = 250\text{ kHz}$		1963		pF
C_{oss}	Output Capacitance			124		
C_{riss}	Reverse Capacitance			9		
E_{oss}	Stored Energy in Output Capacitance	$V_{DS} = 0\text{ V to } 800\text{ V}, V_{GS} = 0\text{ V}$		51		μJ
$C_{o(er)}$	Energy Related Output Capacitance			160		pF
$C_{o(tr)}$	Time Related Output Capacitance			261		
$Q_{g(tot)}$	Total Gate Charge	$V_{DS} = 800\text{ V}, I_D = 30\text{ A},$ $V_{GS} = -5\text{ V} / 18\text{ V},$ Inductive load		104		nC
Q_{gs}	Gate to Source Charge			27		
Q_{gd}	Gate to Drain "Miller" Charge			34		
R_G	Internal Gate Resistance	$f = 1\text{ MHz}$		3.5		Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DS} = 800\text{ V}, I_D = 30\text{ A},$ $V_{GS} = -5\text{ V} / 18\text{ V}, R_G = 2\ \Omega,$ FWD : PCH120S20D1, Inductive load		20		ns
t_r	Turn-On Rise Time			15		
$t_{d(off)}$	Turn-Off Delay Time			37		
t_f	Turn-Off Fall Time			8		
E_{on}	Turn-on Switching Energy			210		μJ
E_{off}	Turn-off Switching Energy			98		
E_{tot}	Total Switching Energy			308		

Source-Drain Diode Characteristics

I_S	Maximum Continuous Diode Forward Current			60	A
I_{SM}	Maximum Pulsed Diode Forward Current			160	
V_{SD}	Diode Forward Voltage	$V_{GS} = -5\text{ V}, I_{SD} = 30\text{ A}$		4.1	V
t_{rr}	Reverse Recovery Time	$V_{DD} = 800\text{ V}, I_{SD} = 30\text{ A},$ $di_F/dt = 3000\text{ A}/\mu\text{s}$, Includes Q_{oss}		16	ns
Q_{rr}	Reverse Recovery Charge			240	

Typical Performance Characteristics

Figure 1. On-Region Characteristics $T_J = -40^\circ\text{C}$

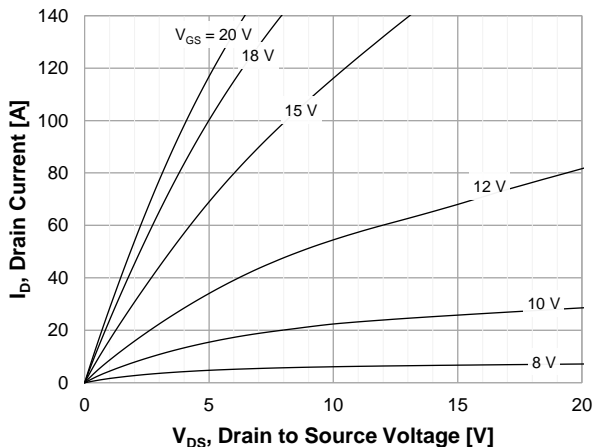


Figure 2. On-Region Characteristics $T_J = 25^\circ\text{C}$

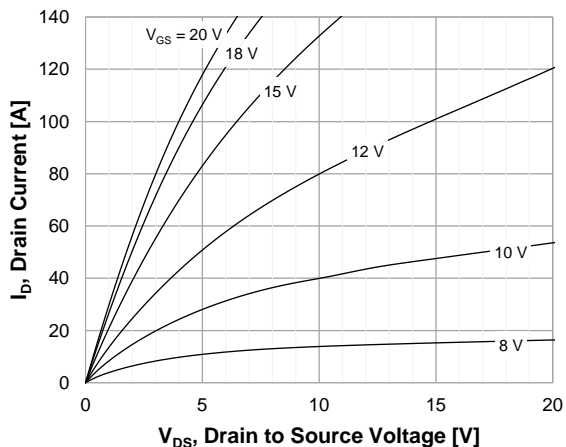


Figure 3. On-Region Characteristics $T_J = 175^\circ\text{C}$

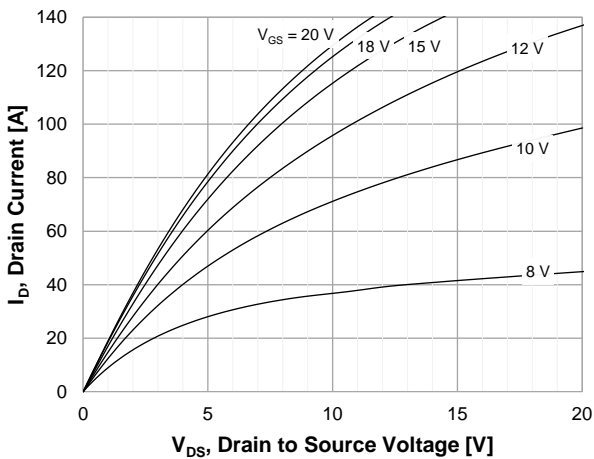


Figure 4. Normalized On-Resistance Characteristics vs. Temperature

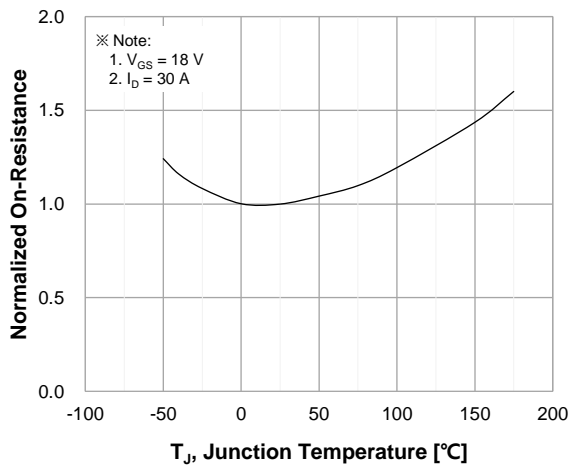


Figure 5. Transfer Characteristics

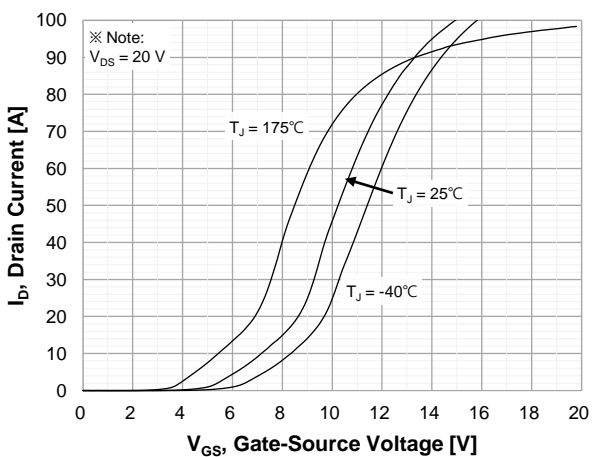
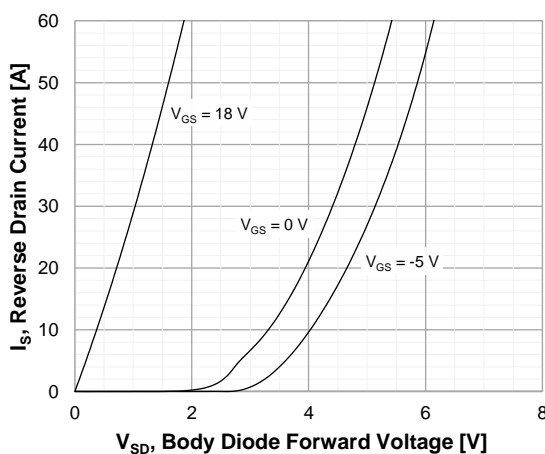


Figure 6. Diode Forward Voltage Characteristics vs. Source-Drain Current $T_J = -40^\circ\text{C}$



Typical Performance Characteristics

Figure 7. Diode Forward Voltage Characteristics vs. Source-Drain Current $T_J = 25^\circ\text{C}$

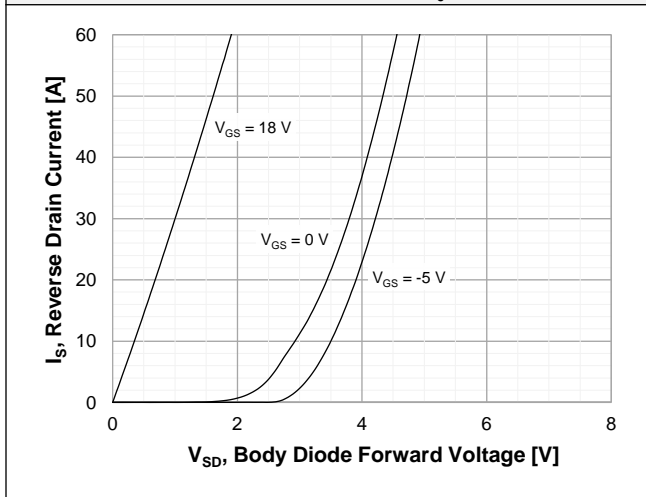


Figure 8. Diode Forward Voltage Characteristics vs. Source-Drain Current $T_J = 175^\circ\text{C}$

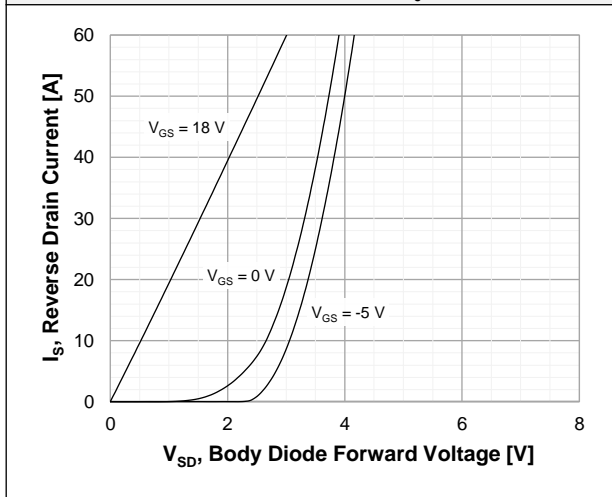


Figure 9. Threshold Voltage vs. Temperature

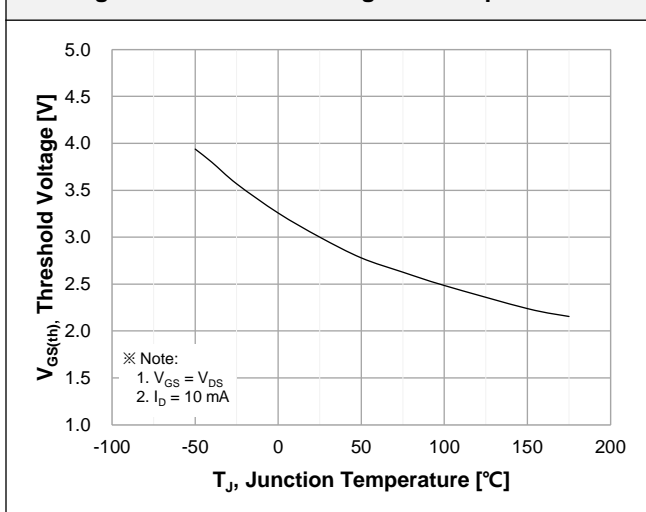


Figure 10. Gate Charge Characteristics

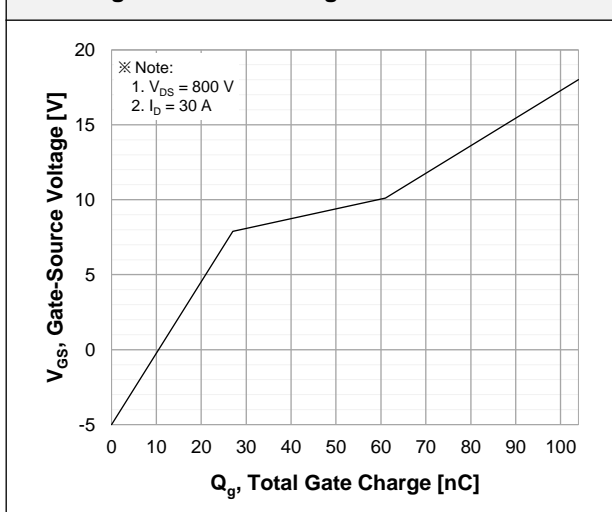


Figure 11. Stored Energy in Output Capacitance

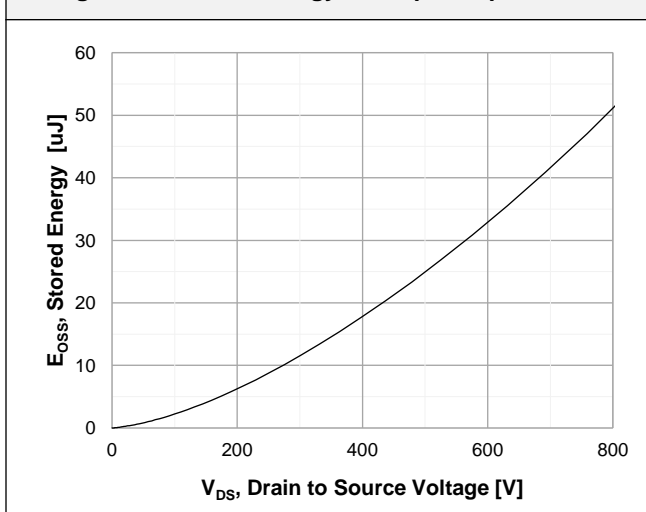
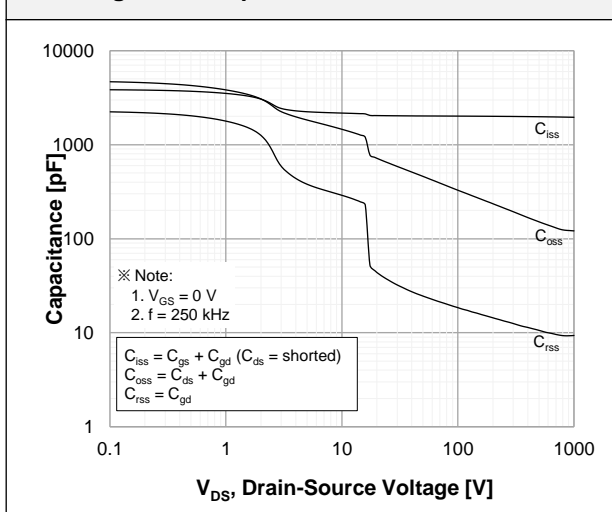
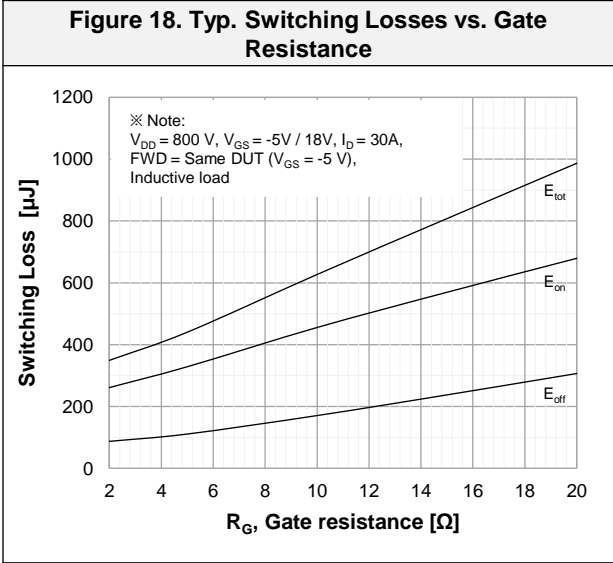
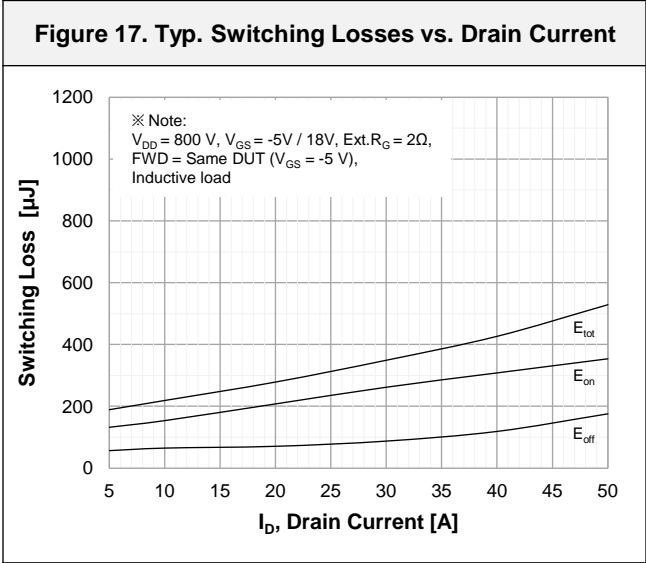
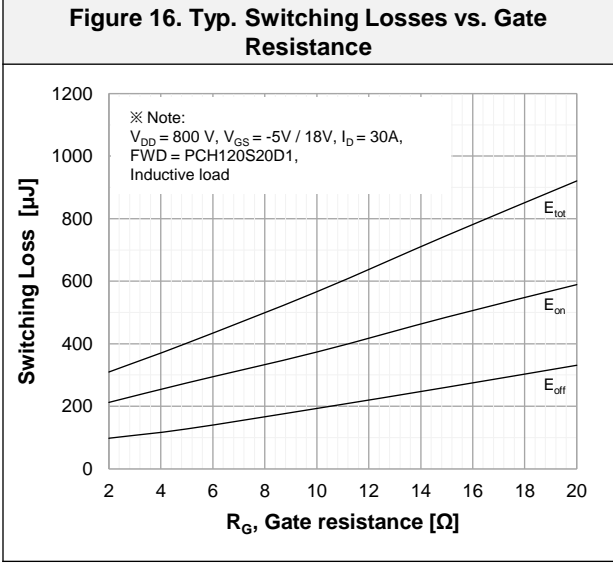
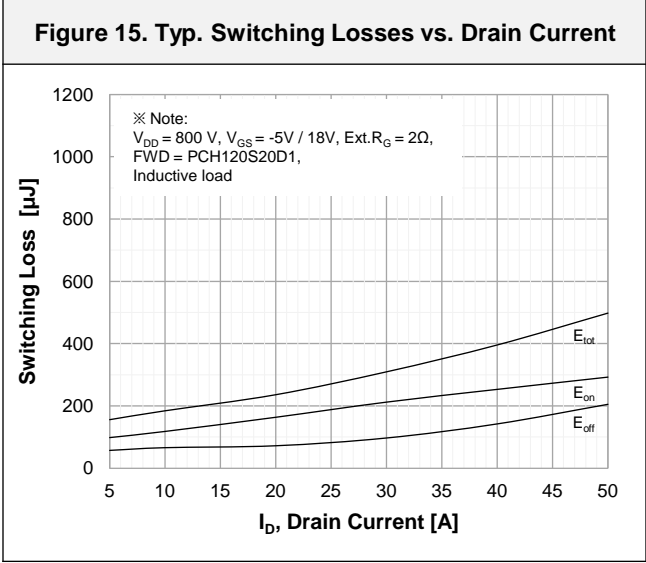
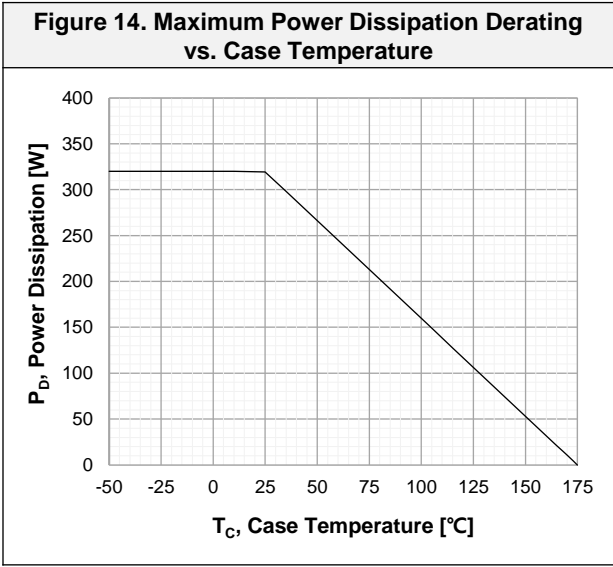
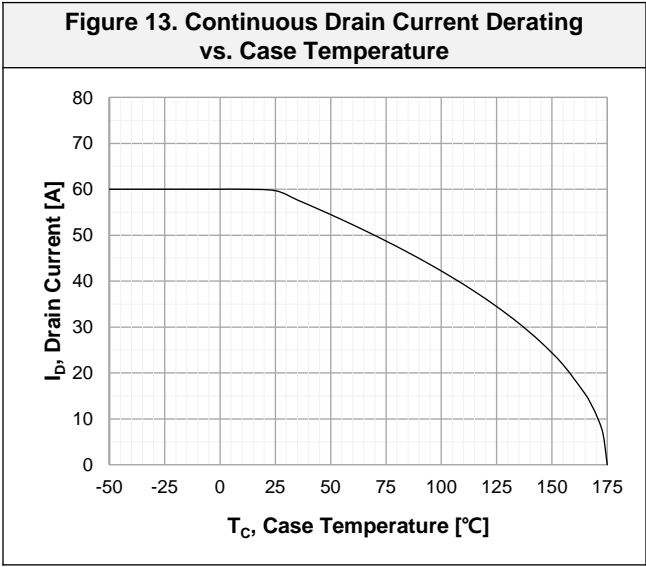


Figure 12. Capacitance Characteristics



Typical Performance Characteristics



Typical Performance Characteristics

Figure 19. Maximum Safe Operating Area

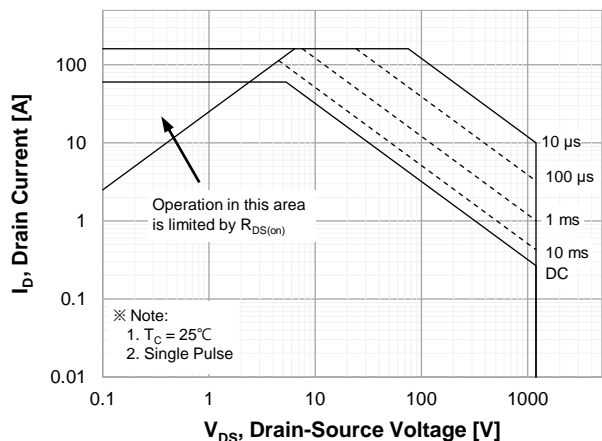


Figure 20. Transient Thermal Response Curve

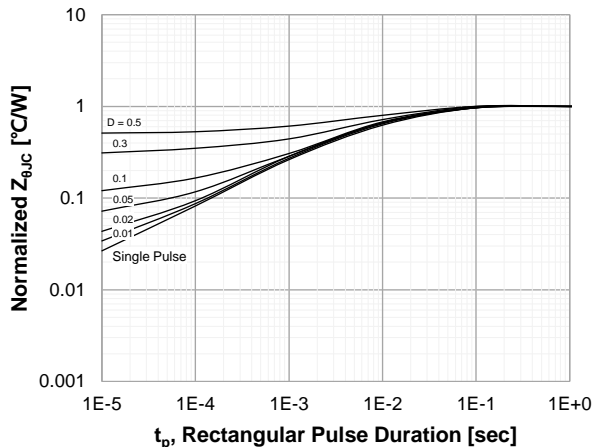


Figure 21. Inductive Load Switching Test Circuit and Waveforms

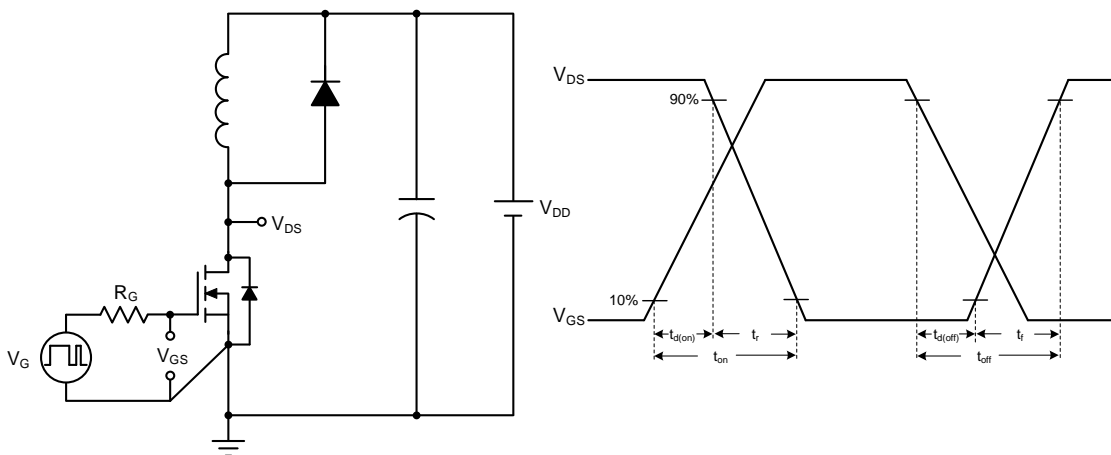
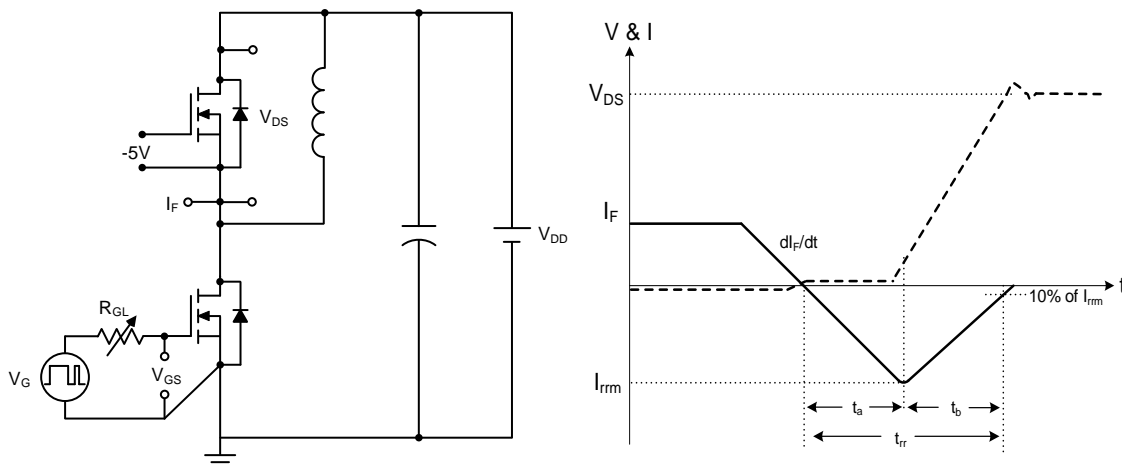
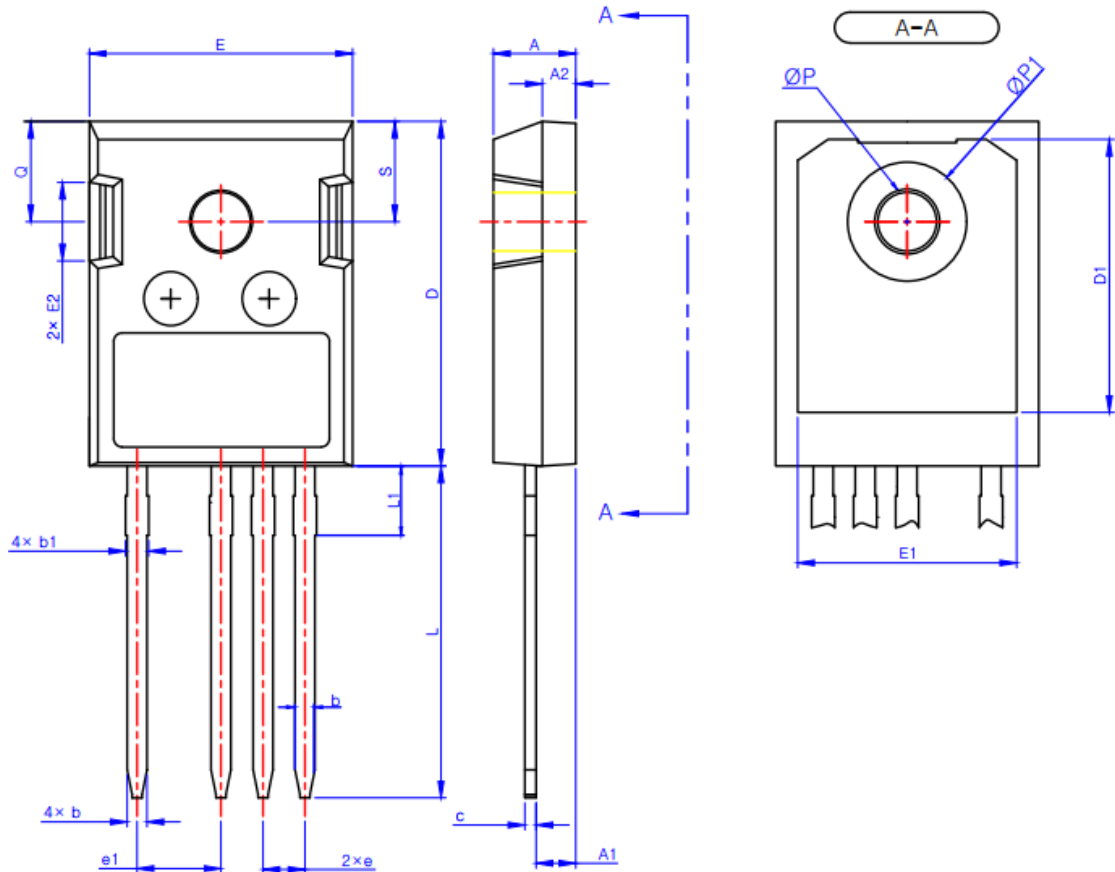


Figure 22. Peak Diode Recovery dv/dt Test Circuit and Waveforms



Package Outlines TO-247-4L



SYMBOL	MIN	MAX
A	4.80	5.20
A1	2.29	2.54
A2	1.90	2.10
b	1.10	1.30
b1	1.30	1.50
c	0.50	0.70
D	20.80	21.10
D1	17.43	17.83
E	15.75	16.13
E1	13.06	13.46
E2	4.32	4.83
e	2.54 BSC	
e1	5.08 BSC	
L	19.85	20.25
L1	-	4.49
ØP	3.55	3.65
ØP1	7.00	7.40
Q	5.59	6.19
S	6.15 BSC	

* Dimensions in millimeters